Se	earch	Note	es
RI IINII AR	IAI CHAAA HI	OO IIIIO PIIA	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/533,651	TAKEUCHI, KESATOSHI
Examiner	Art Unit
Dang D. Le	2834

	SEARCHED			
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED		
Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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